





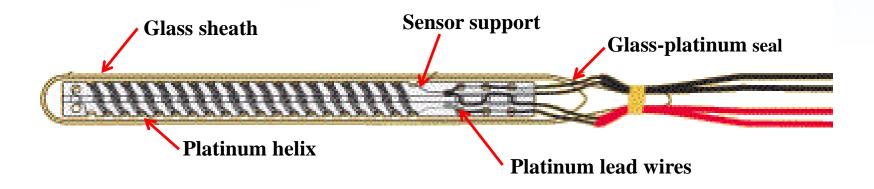
Mechanical Robustness of Cryogenic Temperature Sensors Packaged in a Flat, Hermetically Sealed Package

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Background – Strain Free Mounting

 Historically, cryogenic thermometers required strain free mounting for optimum stability



Fluke 5686 Glass Capsule Standard Platinum Resistance Thermometer Construction



Background

- The most stable devices were fragile and subject to damage from mechanical shock
- True for Platinum, Rhodium-Iron, and Germanium resistance thermometers
- With a small sacrifice in stability, newer devices can be packaged much more robustly

This work examines the mechanical robustness of cryogenic temperature sensors mounted in a flat, hermetically sealed package



Device types tested in -SD package

- All devices manufactured by Lake Shore Cryotronics, Inc.
- 2 Models packaged in flat, hermetically sealed –SD package:
 - CernoxTM model CX-1050-SD
 - Diode model DT-670-SD



Copper or Kovar leads

Gold wire

Alumina body and lid

Metallization

Sapphire base

Solder attach

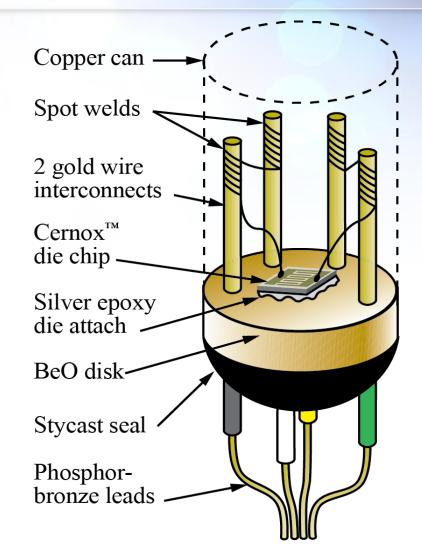
Die Chip



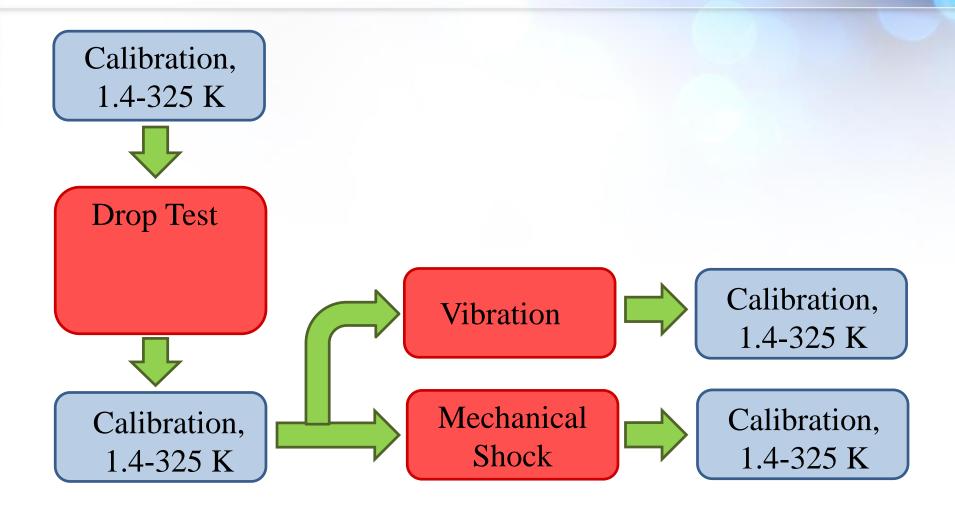
Device type tested in copper A-can

 For comparison, also tested a CernoxTM model CX-1050-AA

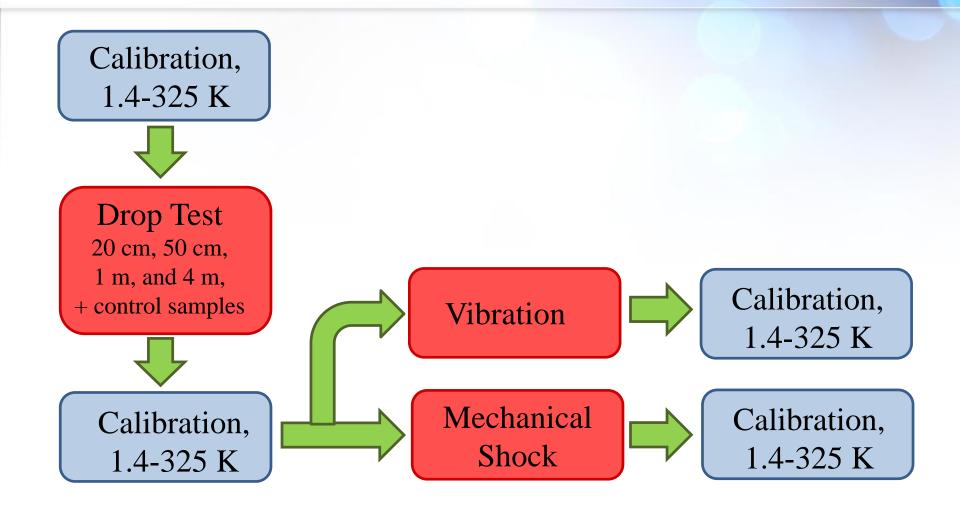




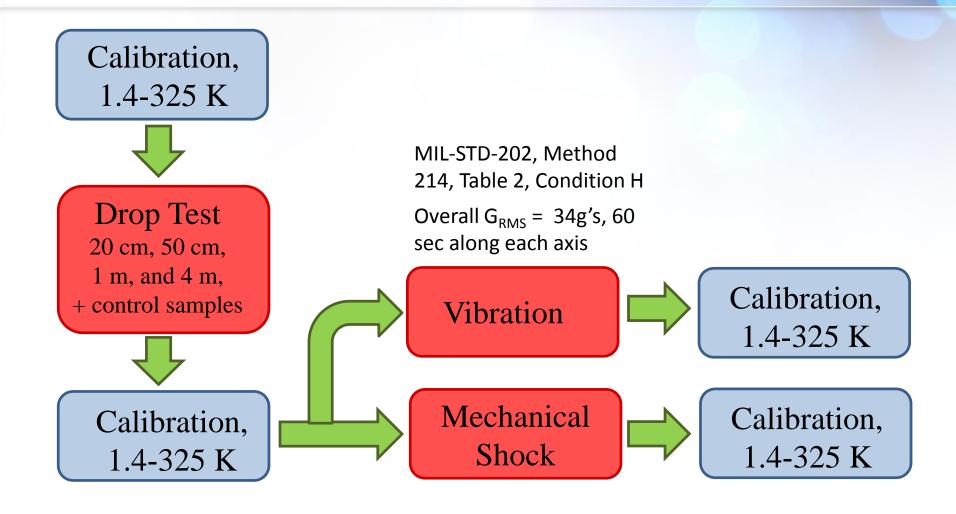




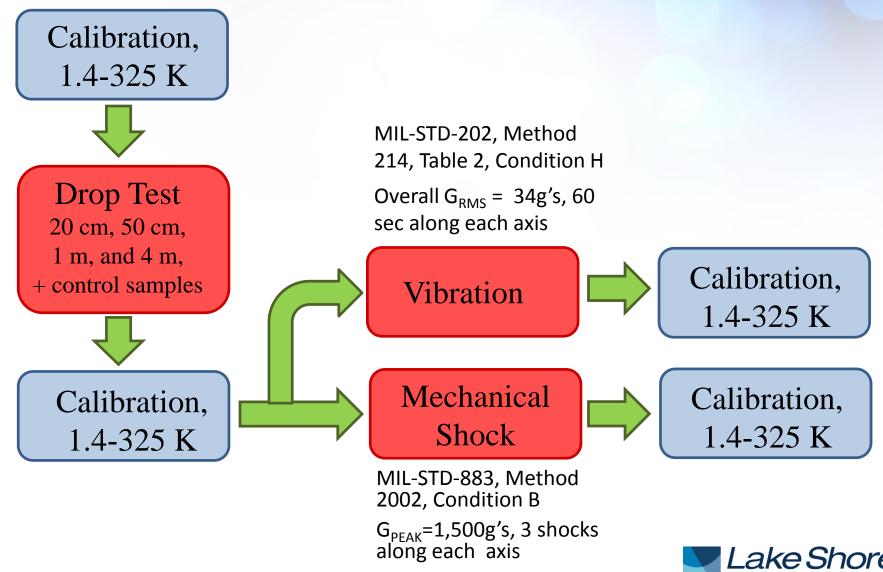






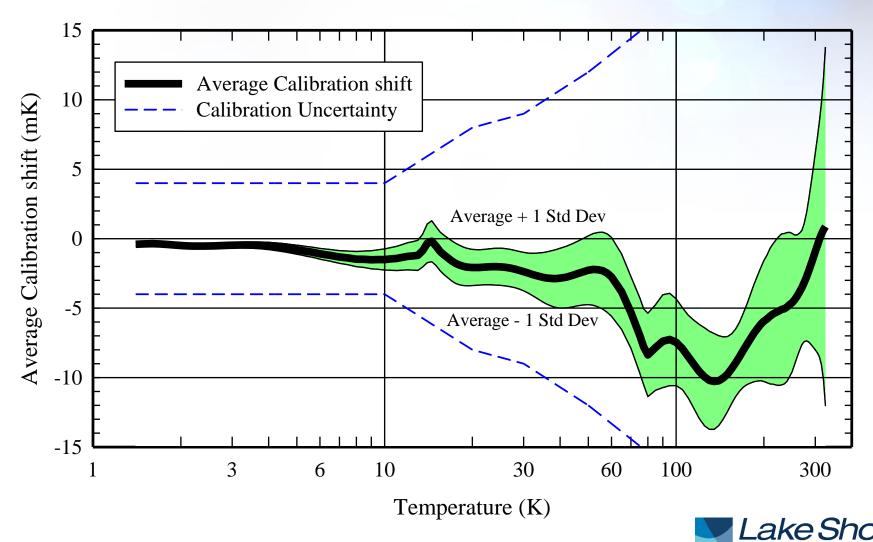






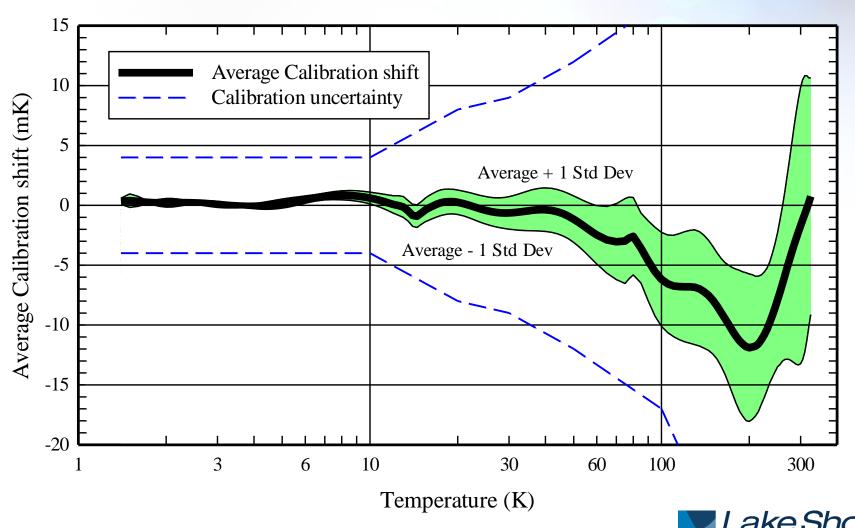
CX-1050-SD Drop Test Results

No discernable effects for any drop height



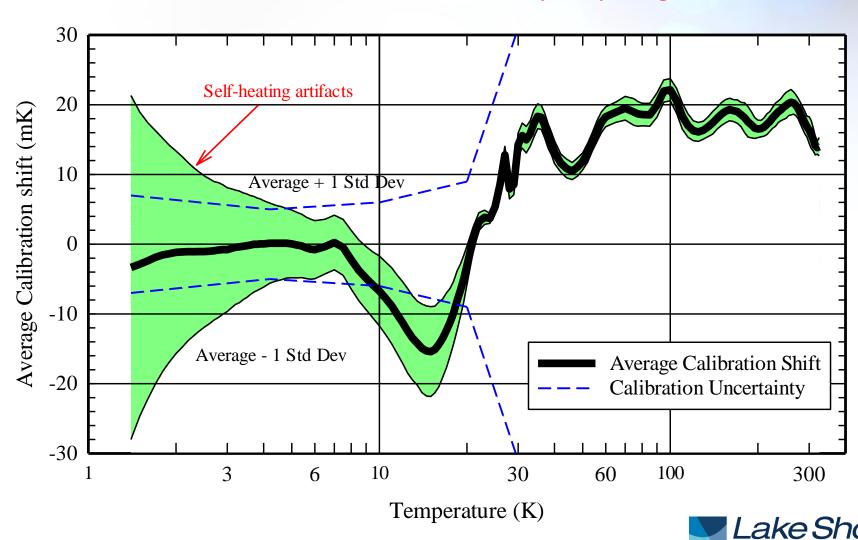
CX-1050-SD Vibration/Mechanical Shock Results

No discernable effects from vibration or mechanical shock



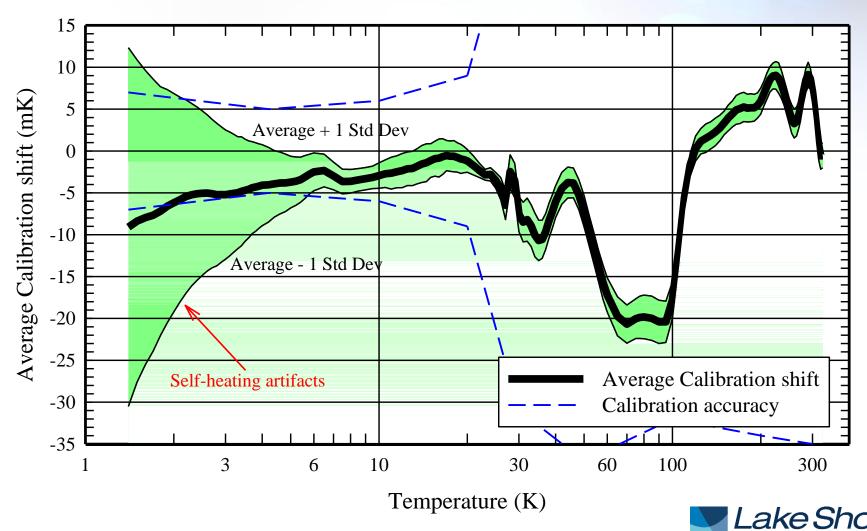
DT-670-SD Drop Test Results

No discernable effects for any drop height



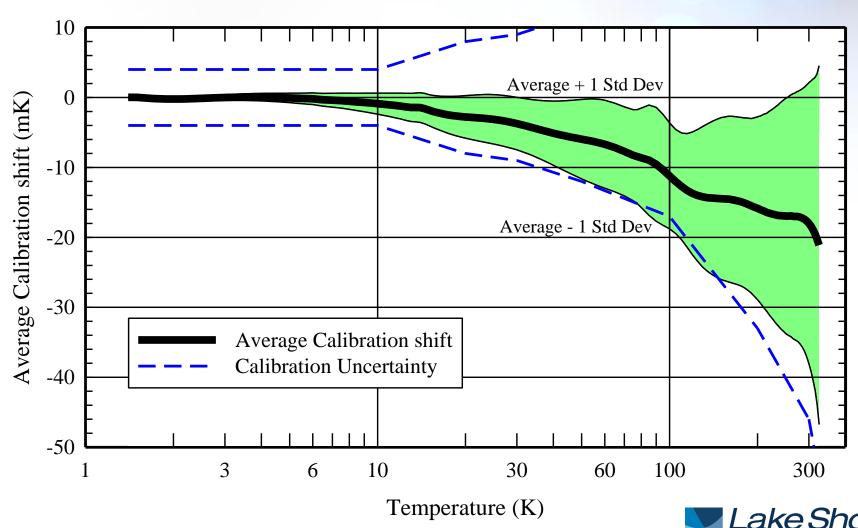
DT-670-SD Vibration/Mechanical Shock Results

No discernable effects from vibration or mechanical shock



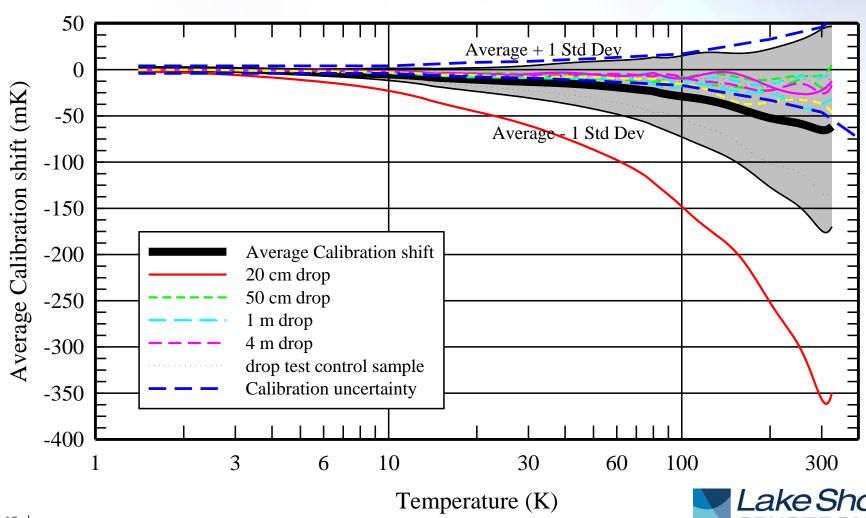
CX-1050-AA Drop Test Results

No discernable effects for any drop height



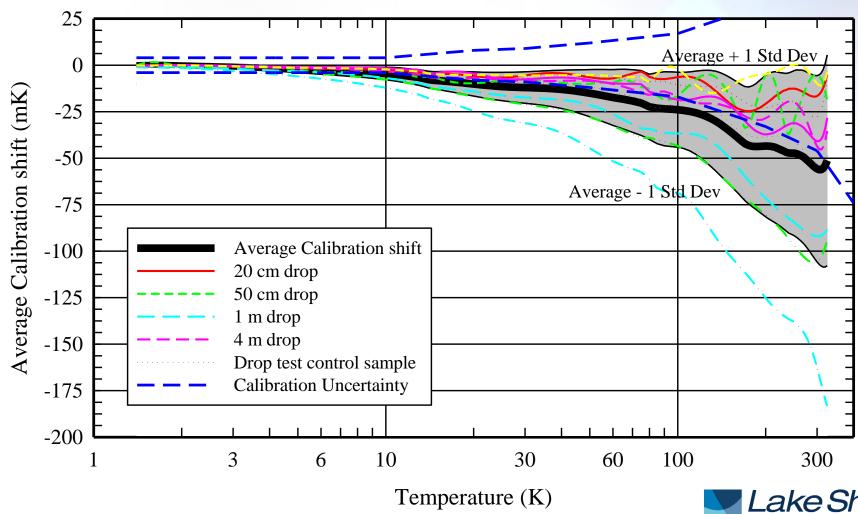
CX-1050-AA Vibration Test Results

Negative trend in ΔT , but results skewed by two devices. Offset uncorrelated to initial drop height.

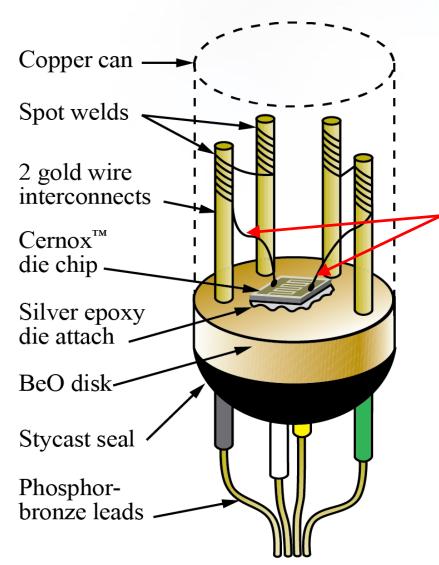


CX-1050-AA Mechanical Shock Test Results

Negative trend in ΔT , but results skewed by three devices. Offset uncorrelated to initial drop height.



CX-1050-AA Offset Cause



Negative $\Delta T \rightarrow Positive \Delta R$;

Most likely cause of increased resistance is stretching of the ≈3 mm long 2-lead portion of the 50 µm diameter gold lead connecting the sensor die to the phosphor bronze post.

(For comparison, the connecting gold leads in the −SD package are 25 μm diameter by ≈0.75 mm long)



Conclusions

This work has shown:

- For models CernoxTM CX-1050-SD and diode DT-670-SD
 - No discernable effect when dropped from heights up to 4 m
 - No discernable effect from vibration with $G_{RMS} = 34Gs$
 - No discernable effect from mechanical shock of $G_{PEAK} = 1,500Gs$



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 - No discernable effect when dropped from heights up to 4 m
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 - No discernable effect from mechanical shock of $G_{PFAK} = 1,500Gs$
- For model CernoxTM CX-1050-AA
 - No discernable effect when dropped from heights up to 4 m
 - A negative trend in ΔT after vibration with average offset approaching -60 mK at 300 K, but uncorrelated to drop height
 - A negative trend in ΔT after mechanical shock with average offset approaching -60 mK at 300 K, but uncorrelated to drop height



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